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Development of 3D-VLSI System with Self-Test and Self-Repair Function

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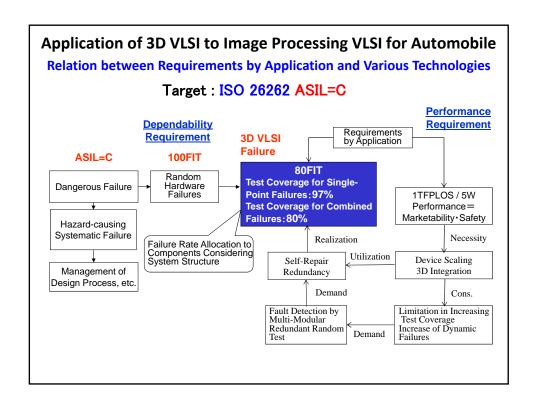
Setting Target for High Performance Image Processing System to Guarantee Safety in Automobile Driving Assist

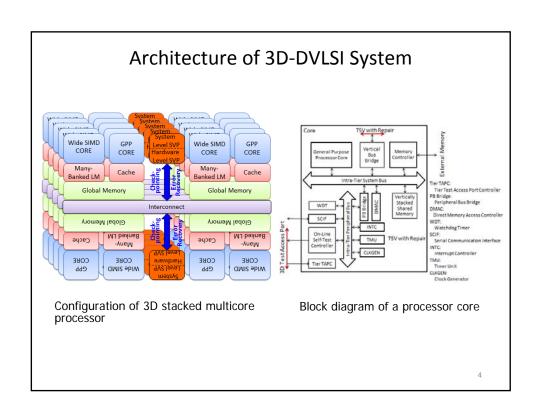


Visual Information Processing Unit with 3D Stacked Structure



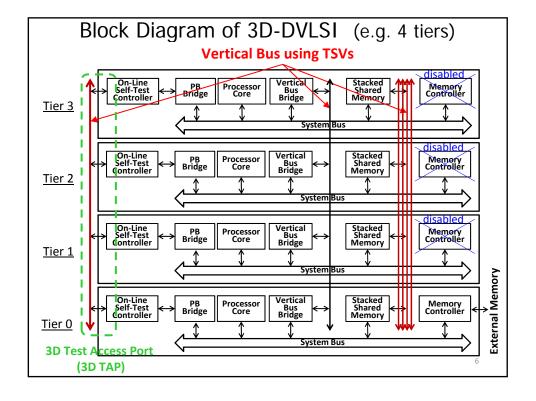
- Number of camera: 2
- Measuring distance: 0~100m
- Base line length: 12cm
- Focus length: 6.5cm
- Pixel resolution: SXGA
- Window size: 48 pixels x 31 lines
- Reconfiguration points: 30,000
- Matching accuracy: 1/20 Pixel
- Z Axis resolution
 - (Measuring distance accuracy): 80cm resolution at 50m ahead 3m resolution at 100m ahead
- Calculating ability: ~1TFLOPS

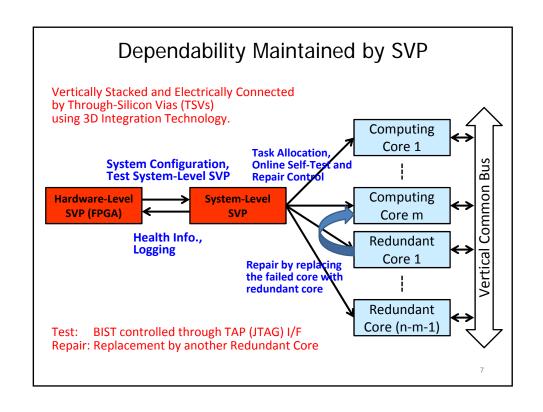


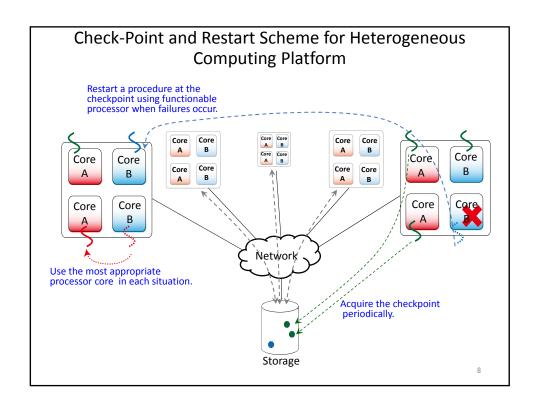


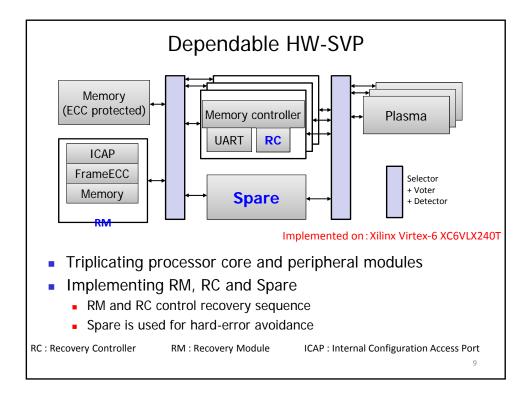
Purpose for Fabrication of Prototype 3D-Stacked Graphics Processor

- Evaluation of self-test control
 - **BIST operation control**
- Verification of design methodology for TSV circuits
 - DFT for TSV
 - **▶** Electrical conduction pass test for each TSV
 - > TSV repair method
 - > Arrangement of repair TSVs for a group of signal TSVs
 - Replacement of failure TSVs by repair TSVs which pass electrical conduction test
- Integration of functional blocks by TSVs
 - Vertical buses/ Vertical bus bridges
 - Integration of 3D shared memory
 - Maintaining of consistency
 - ☐ Maintaining consistency by updating memory contents at appropriate intervals using memory-update vertical buses
 - Memory access control by prohibiting memory access for updating memory area with each line.
 - □ Providing vertical buses for memory updating to each page
 - No memory replacement function as in cache memory









Summary

- We proposed a new dependable architecture for 3D-VLSI in which a system supervisor processor (Sys-SVP) controls self-test and selfrepair circuits and a hardware system supervisor processor (HW-SVP) controls Sys-SVP to maintain dependability.
- We established a self-repair scheme with soft-error recovery using dynamic reconfiguration and hard-error avoidance using partial reconfiguration to guarantee dependability of HW-SVP.
- We employed a checkpoint and restart scheme to migrate all function in a failure processor layer to another processor layer to maintain dependability and proposed a new algorithm to dynamically perform self-test and migration to maintain performance in 3D stacked graphics processor.
- We introduced a new 3D DfT (Design for Test) architecture with online self-test using Sys-SVP through 3D TAP (test access port) based on IEEE 1149.1. into 3D stacked graphics processor to maintain dependability.
- We introduced redundancy methods to guarantee the reliability of TSVs (Through Si Vias) in 3D-VLSI.
- We evaluate power efficiency of 3D-VLSI assuming the application to image processing for automobile of obstacle detection using stereo vision with POC (Phase-Only Correlation)-based correspondence matching.

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